Sheet 1 of 1 APPLICATION NUMBER ATTY, DOCKET NO. FORM PT9-1449 (Modified) TS0926 (US) 09/664,293 **APPLICANT** LIST OF INFORMATION PROVIDED JAN 1 6 2001 M. B. H. Van Crijnen-Beers BY APPLICANT FILING DATE **GROUP ART UNIT** (Use several sheets if necessary) September 18, 2000 QADEMP REFERENCE DESIGNATION U.S. PATENT DOCUMENTS Filing Date Examiner Document No. Date **Patentee** Class **Subclass** if Appropriate Initial 10/1/91 502 AA Absil et al. 64 5,053,374 WB AB 5,157,191 10/20/92 Bowes et al. 585 533 WG 7/7/64 208 120 AC 3,140,249 Plank et al. W6 7/7/64 208 120 Plank et al. AD 3,140,251 WC ΑE 3,140,253 7/7/64 Plank et al. 208 120 WG 9/8/98 Grandvallet et al. 208 171 AF 5,804,058 WG 9/10/96 208 AG 5,554,274 Degnan et al. 111

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**EXAMINER** 

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

<sup>1.</sup> The attached cited information should not be construed as an admission that any of the above items are prior art to the subject invention.

<sup>2.</sup> This is not a representation that a search has been made.

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		LIST OF INFORMATION PROVIDED BY APPLICANT	APPLICANT M. B. H. Van Crijnen-Beers				
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2. This is not a representation that a search has been made.

<sup>\*</sup>Date when provided in xx/yy/zz format represents DAY/MONTH/YEAR.